

FORM PTO-1449 (SUBSTITUTE)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEAttorney Docket No.:  
E-41482Applic. No.  
10/030,238

Applicant

Steffen Burkhardt et al.

Filing Date  
December 31, 2001

Group Art Unit

OIP  
INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT  
(37 CFR 1.98(b))

APR 04 2002

## U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
ELF	A	4,752,897	06/21/88	Zoeller et al.			
ELF	B	5,745,365	04/28/98	Parker			
ELF	C	5,899,959	05/04/99	Shields			
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## FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES   NO
ELF	J	22 00 293 C2	08/03/72	Germany			X
ELF	K	43 43 058 A1	06/22/95	Germany			X
ELF	L	195 18 804 A1	12/21/95	Germany			X
ELF	M	196 32 269 A1	02/13/97	Germany			X
ELF	N	197 20 307 A1	11/19/98	Germany			X

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

ELF	O	Reinhard Rinn et al.: "Parsytec HTS-2, Defect Detction and Classification through Software vs. Dedicated Hardware", Part of the IS&T/SPIE Conference on Real-Time Imaging IV, San Jose, California, January 1999, SPIE, Vol. 3645, pp. 110-121
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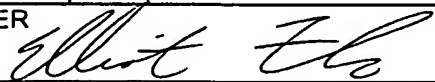
## FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES   NO
ELF	J	0 176 661 A2	04/09/86	Europe			X
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